

The New Dimension in Electron Microscopy

Hitachi's New SEM & TEM Models at M&M 2012



NEW! SU3500 Scanning Electron Microscope

Intuitive Operation

Wide-screen GUI and fast auto image optimization functions (7 seconds) via "delegation" technology

Unparalleled Image Quality

All new electron optics design with best-in-class image sharpness

Ultra Variable-Pressure Detector

Image surface information at low accelerating voltages and low vacuum

Stereoscopic Image Function

Point and click for seamless, real-time "3D" image observation



NEW! HT7710 High-Performance BF/DF STEM

STEM Performance for Soft/Hybrid Materials

40-120kV with a magnification range of 100-800,000X and image recording resolutions up to 5120 X 3840

High Magnification and Large FOV STEM

Ideal for high-resolution lattice imaging, bulk crystal structure, and nanoparticle analysis

Flexible Port Configurations

BF/DF STEM, EDS detectors, and cameras for high-throughput imaging and compositional data

Intuitive STEM GUI and Automation Features

All STEM images instantly archived in Hitachi's EMIP database software

Click or call to learn about our new 3-year warranty promotion for select SEM and TEM models!*

Hitachi—The Reliability Leader in Electron Microscopy

* Offer valid in the United States only. Requires acceptance of additional Terms & Conditions. Hitachi High Technologies America reserves the right to terminate or modify this warranty promotion at any time. Contact us for details.

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Booth # 532

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<https://doi.org/10.1017/S1431927612001705> Published online by Cambridge University Press

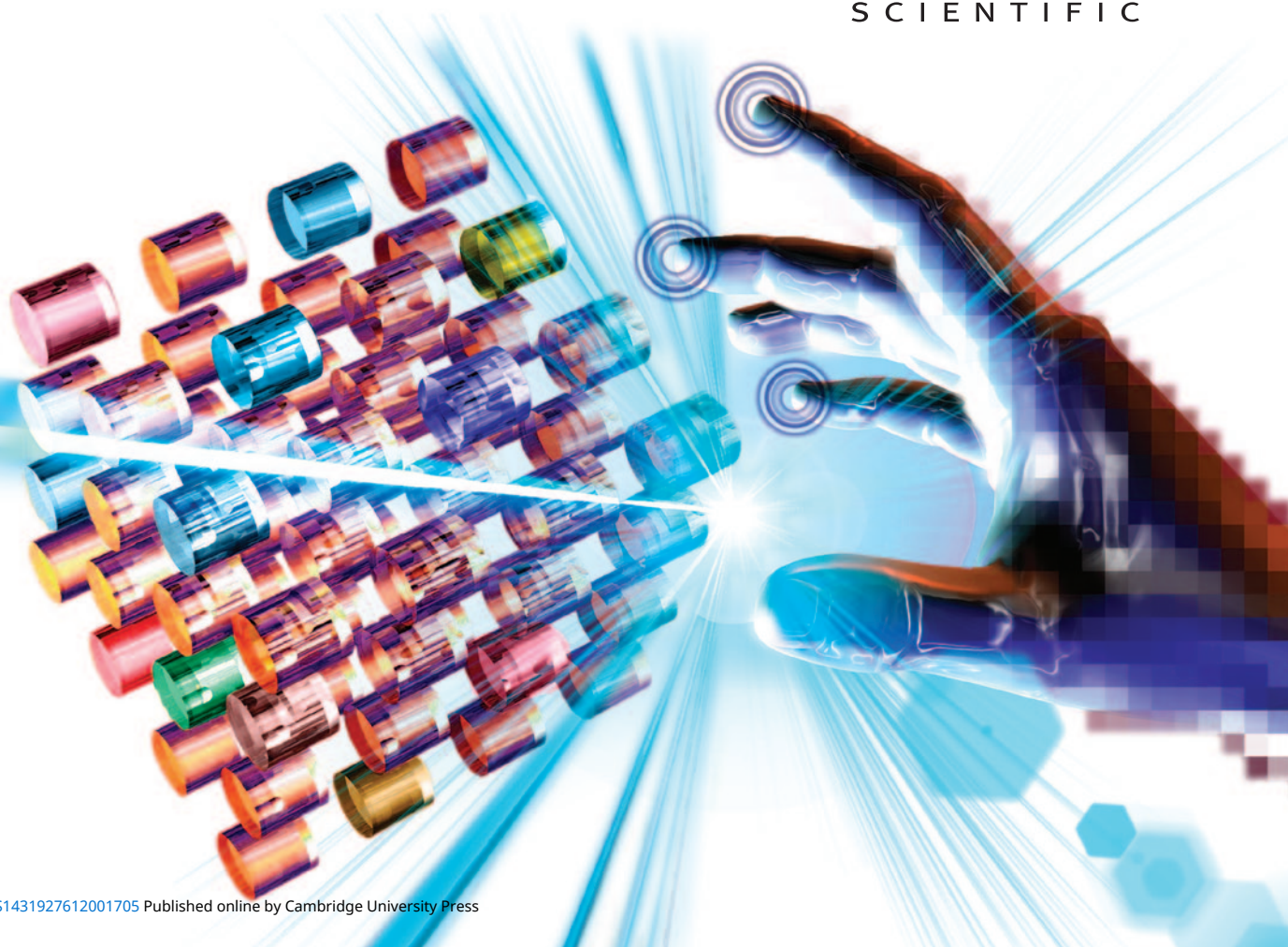
True system integration.

Electron microscopy laboratories seek maximum productivity and accuracy from microanalysis. Systems need to be intuitive, easy to use and eliminate operator bias. Our long history of innovation has led to the first truly integrated microanalysis system, providing the optimal combination of **EBSD, WDS and EDS detectors**, software and electronics. Collect large amounts of data in the shortest amount of time. Identify phases confidently with a minimum amount of spectra. Move seamlessly through your analysis with one common interface.

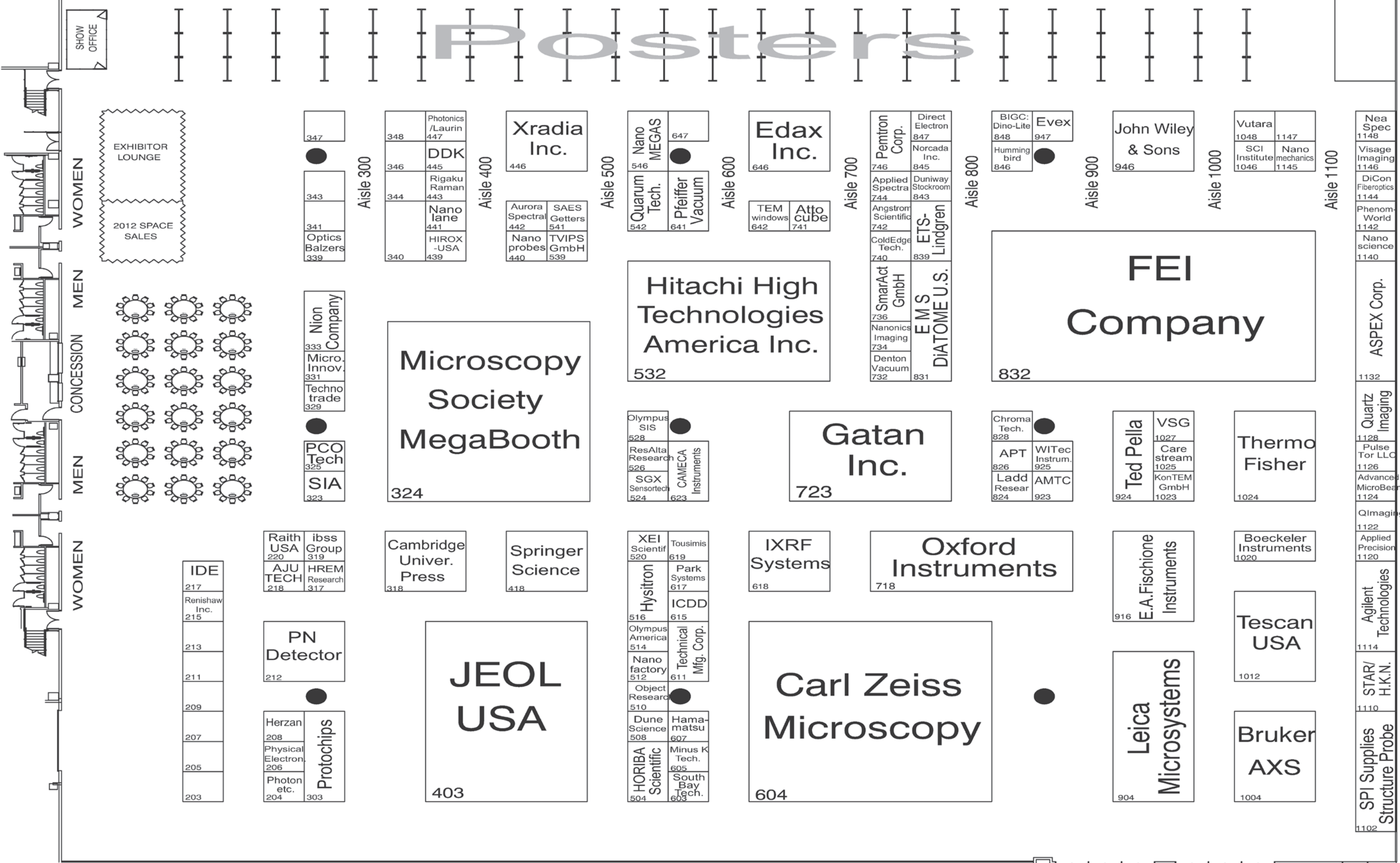
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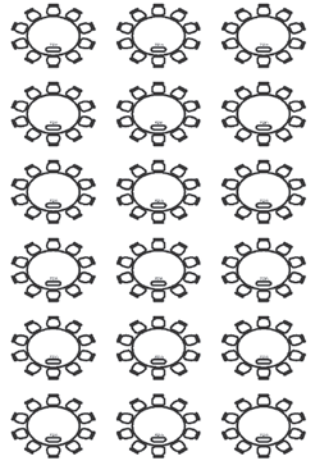
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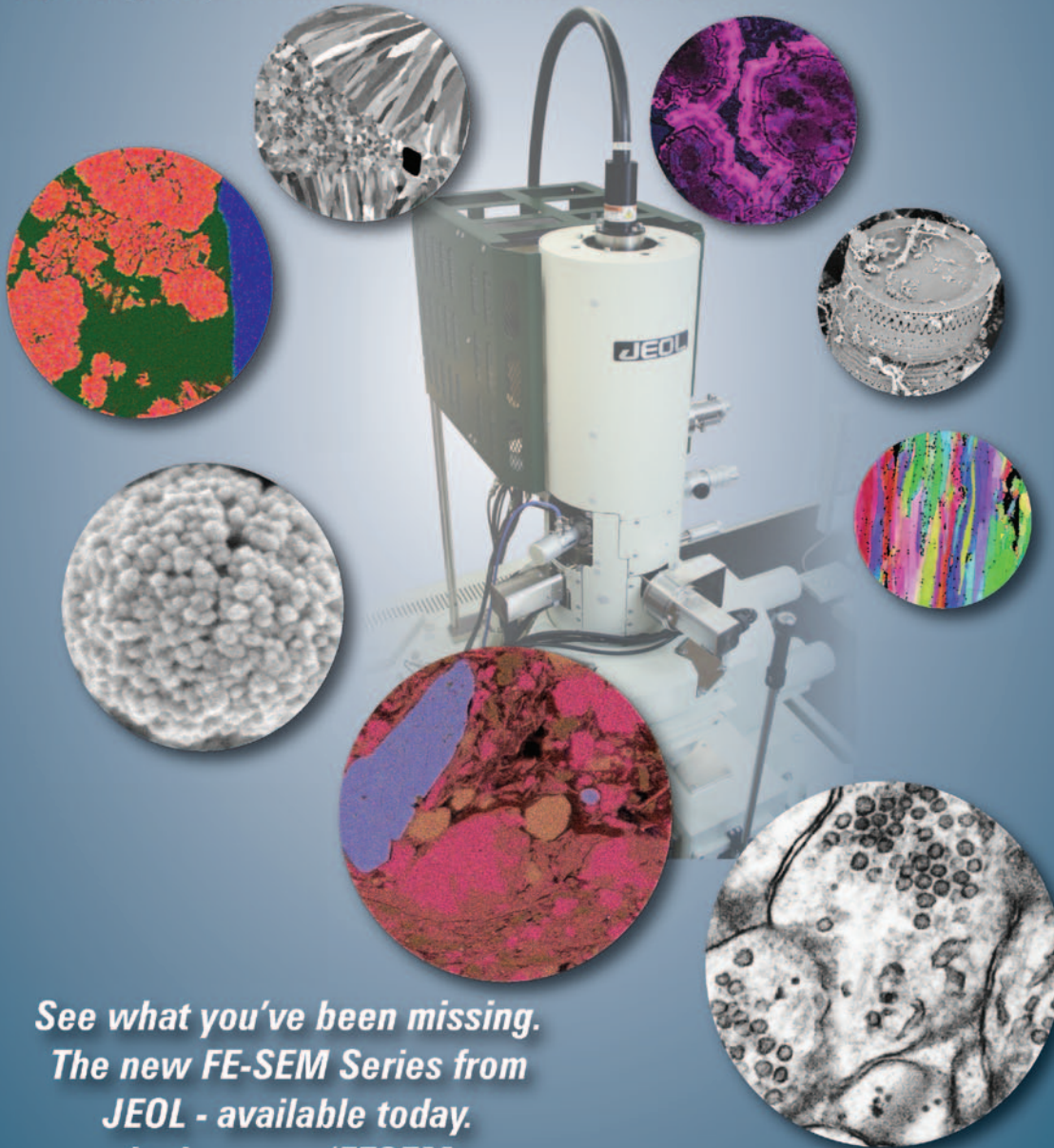
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Ultra-versatility Sub-nm Resolution

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